## **Power MOSFET**

## 60 V, 7.2 m $\Omega$ , 67 A, Single N-Channel

NVMFS5H663NLWF - Wettable Flank Option for Enhanced Optical Inspection.

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	٧
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	67	Α
Current R <sub>θJC</sub> (Notes 1, 3)		T <sub>C</sub> = 100°C		47	
Power Dissipation R <sub>0</sub> JC (Note 1)		T <sub>C</sub> = 25°C	$P_{D}$	63	W
		T <sub>C</sub> = 100°C		31.3	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	16.2	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)		T <sub>A</sub> = 100°C		11.4	
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	3.7	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.8	
Pulsed Drain Current	$T_A = 25^\circ$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	359	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	52	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 3.8 A)			E <sub>AS</sub>	274	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	2.4	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	41	

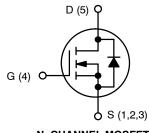
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



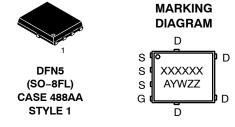
## ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
60 V	7.2 mΩ @ 10 V	07.4
60 V	10 mΩ @ 4.5 V	67 A



**N-CHANNEL MOSFET** 



5H663L = (NVMFS5H663NL) or 663LWF = (NVMFS5H663NLWF)

= Assembly Location Α

Υ = Year W = Work Week = Lot Traceability

## **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> =	= 250 μA	60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				43		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ ,	T <sub>J</sub> = 25 °C			10	μΑ
		V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)				•	•	•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 56 μA		1.2		2.0	٧
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		5.8	7.2	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		8	10	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> =15 V, I <sub>D</sub> = 20 A			64		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE			ı			I.
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 30 V			1131		pF
Output Capacitance	C <sub>OSS</sub>				213		
Reverse Transfer Capacitance	C <sub>RSS</sub>				7.5		
Output Charge	Q <sub>OSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DD</sub> = 30 V			18		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 20 A			8		nC V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 20 A			17		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 20 A			2.2		
Gate-to-Source Charge	Q <sub>GS</sub>				3.8		
Gate-to-Drain Charge	$Q_GD$				1.4		
Plateau Voltage	$V_{GP}$				3.1		
SWITCHING CHARACTERISTICS (Note 5	5)			ı			
Turn-On Delay Time	t <sub>d(ON)</sub>				13.4		
Rise Time	t <sub>r</sub>	Voc = 45 V Vo	oc = 48 V		52.7		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$ $I_{D} = 20 \text{ A}, R_{G}$	$= 2.5 \Omega$		26.2		
Fall Time	t <sub>f</sub>	1			9.5		1
DRAIN-SOURCE DIODE CHARACTERIS	l l						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.84	1.2	
<del>-</del>		VGS = 0 V,	T <sub>J</sub> = 125°C		0.70		<b>'</b>
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 20 \text{ A}$			30.7		
Charge Time	t <sub>a</sub>				17.7		ns
Discharge Time	t <sub>b</sub>				13.1		
Reverse Recovery Charge	Q <sub>RR</sub>				22.8		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

<sup>5.</sup> Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

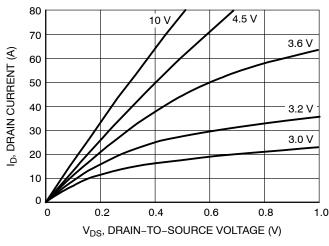


Figure 1. On-Region Characteristics

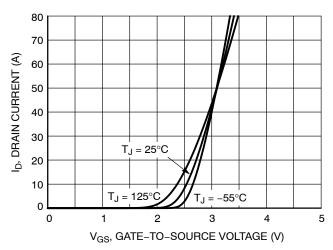


Figure 2. Transfer Characteristics

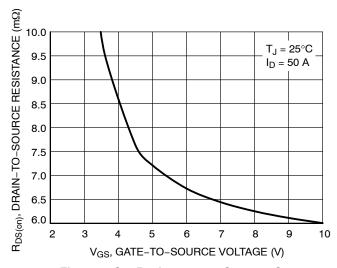


Figure 3. On-Resistance vs. Gate-to-Source Voltage

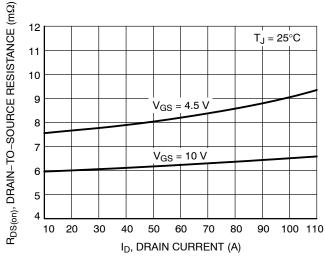


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

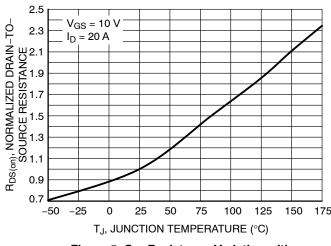


Figure 5. On–Resistance Variation with Temperature

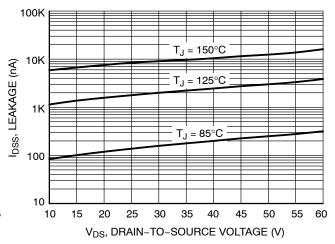


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

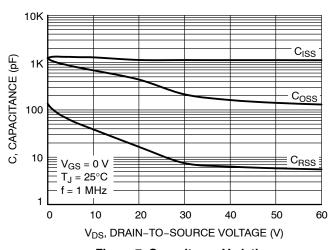


Figure 7. Capacitance Variation

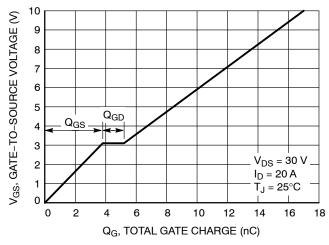
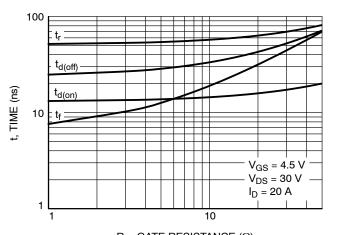


Figure 8. Gate-to-Source Voltage vs. Total Charge



 $R_G$ , GATE RESISTANCE ( $\Omega$ )

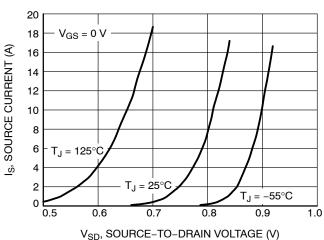


Figure 10. Diode Forward Voltage vs. Current



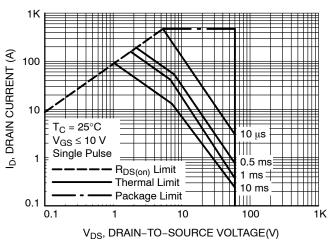


Figure 11. Maximum Rated Forward Biased Safe Operating Area

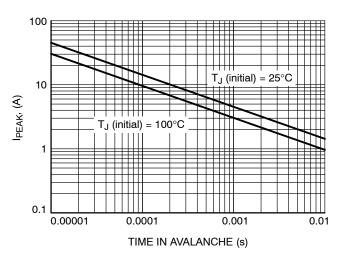


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

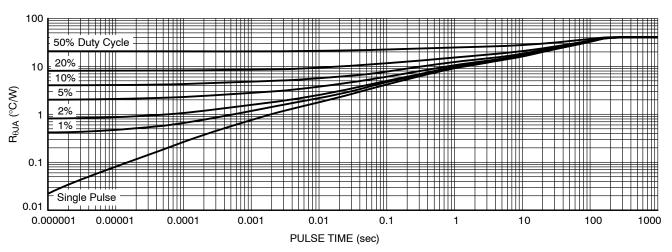


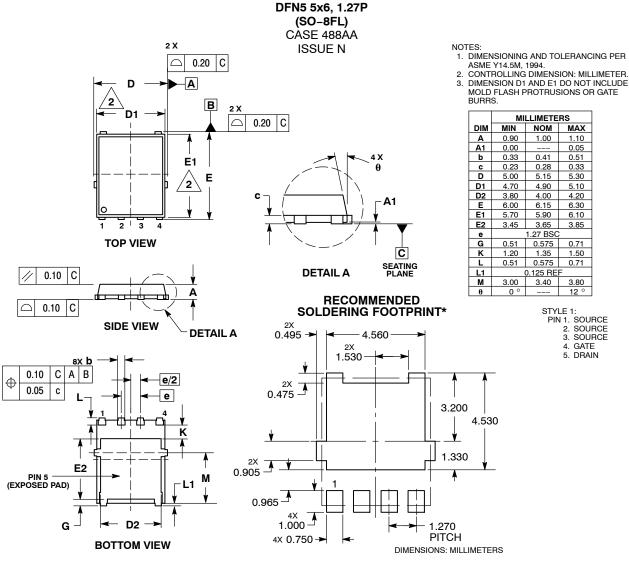
Figure 13. Thermal Characteristics

### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS5H663NLT1G	5H663L	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS5H663NLWFT1G	663LWF	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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